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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex® -M7
Core Size	32-Bit Single-Core
Speed	216MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I ² C, IrDA, LINbus, MMC/SD/SDIO, QSPI, SAI, SPDIF, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	82
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f767vgt6

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2.7 DMA controller (DMA)

The devices feature two general-purpose dual-port DMAs (DMA1 and DMA2) with 8 streams each. They are able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. They feature dedicated FIFOs for APB/AHB peripherals, support burst transfer and are designed to provide the maximum peripheral bandwidth (AHB/APB).

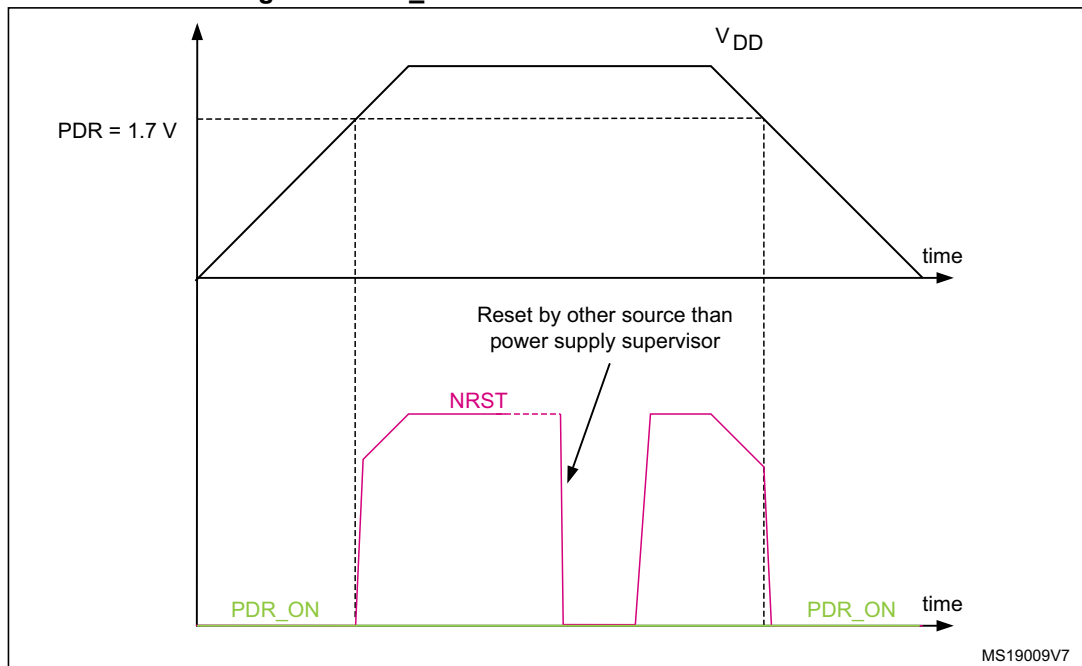
The two DMA controllers support circular buffer management, so that no specific code is needed when the controller reaches the end of the buffer. The two DMA controllers also have a double buffering feature, which automates the use and switching of two memory buffers without requiring any special code.

Each stream is connected to dedicated hardware DMA requests, with support for software trigger on each stream. The configuration is made by software and the transfer sizes between the source and the destination are independent.

The DMA can be used with the main peripherals:

- SPI and I²S
- I²C
- USART
- General-purpose, basic and advanced-control timers TIMx
- DAC
- SDMMC
- Camera interface (DCMI)
- ADC
- SAI
- SPDIFRX
- Quad-SPI
- HDMI-CEC
- JPEG codec
- DFSDM1

Figure 7. PDR_ON control with internal reset OFF



2.19 Voltage regulator

The regulator has four operating modes:

- Regulator ON
 - Main regulator mode (MR)
 - Low power regulator (LPR)
 - Power-down
- Regulator OFF

2.19.1 Regulator ON

On packages embedding the BYPASS_REG pin, the regulator is enabled by holding BYPASS_REG low. On all other packages, the regulator is always enabled.

There are three power modes configured by software when the regulator is ON:

- MR mode used in Run/sleep modes or in Stop modes
 - In Run/Sleep modes

The MR mode is used either in the normal mode (default mode) or the over-drive mode (enabled by software). Different voltages scaling are provided to reach the best compromise between maximum frequency and dynamic power consumption. The over-drive mode allows operating at a higher frequency than the normal mode for a given voltage scaling.
 - In Stop modes

The MR can be configured in two ways during stop mode:
 MR operates in normal mode (default mode of MR in stop mode)
 MR operates in under-drive mode (reduced leakage mode).

Table 6. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary output	Max interface clock (MHz)	Max timer clock (MHz) ⁽¹⁾
Advanced -control	TIM1, TIM8	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	Yes	108	216
General purpose	TIM2, TIM5	32-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	54	108/216
	TIM3, TIM4	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	54	108/216
	TIM9	16-bit	Up	Any integer between 1 and 65536	No	2	No	108	216
	TIM10, TIM11	16-bit	Up	Any integer between 1 and 65536	No	1	No	108	216
	TIM12	16-bit	Up	Any integer between 1 and 65536	No	2	No	54	108/216
	TIM13, TIM14	16-bit	Up	Any integer between 1 and 65536	No	1	No	54	108/216
Basic	TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No	54	108/216

1. The maximum timer clock is either 108 or 216 MHz depending on TIMPRE bit configuration in the RCC_DCKCFGR register.

Table 8. USART implementation (continued)

features ⁽¹⁾	USART1/2/3/6	UART4/5/7/8
Smartcard mode	X	-
Single-wire half-duplex communication	X	X
IrDA SIR ENDEC block	X	X
LIN mode	X	X
Dual clock domain	X	X
Receiver timeout interrupt	X	X
Modbus communication	X	X
Auto baud rate detection	X	X
Driver Enable	X	X

1. X: supported.

2.26 Serial peripheral interface (SPI)/inter- integrated sound interfaces (I2S)

The devices feature up to six SPIs in slave and master modes in full-duplex and simplex communication modes. SPI1, SPI4, SPI5, and SPI6 can communicate at up to 54 Mbits/s, SPI2 and SPI3 can communicate at up to 25 Mbit/s. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable from 4 to 16 bits. The SPI interfaces support NSS pulse mode, TI mode and Hardware CRC calculation. All the SPIs can be served by the DMA controller.

Three standard I²S interfaces (multiplexed with SPI1, SPI2 and SPI3) are available. They can be operated in master or slave mode, in simplex communication modes, and can be configured to operate with a 16-/32-bit resolution as an input or output channel. Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I²S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

All I2Sx can be served by the DMA controller.

2.27 Serial audio interface (SAI)

The devices embed two serial audio interfaces.

The serial audio interface is based on two independent audio subblocks which can operate as transmitter or receiver with their FIFO. Many audio protocols are supported by each block: I2S standards, LSB or MSB-justified, PCM/DSP, TDM, AC'97 and SPDIF output, supporting audio sampling frequencies from 8 kHz up to 192 kHz. Both subblocks can be configured in master or in slave mode.

In master mode, the master clock can be output to the external DAC/CODEC at 256 times of the sampling frequency.

The two sub-blocks can be configured in synchronous mode when full-duplex mode is required.

- 16-bit RGB, configurations 1, 2, and 3
 - 18-bit RGB, configurations 1 and 2
 - 24-bit RGB
- Programmable polarity of all LTDC interface signals
- Extended resolutions beyond the DPI standard
- Maximum resolution of 800x480 pixels:
- Maximum resolution is limited by available DSI physical link bandwidth:
 - Number of lanes: 2
 - Maximum speed per lane: 500 Mbps1Gbps

Adapted interface features

Support for sending large amounts of data through the memory_write_start(WMS) and memory_write_continue(WMC) DCS commands

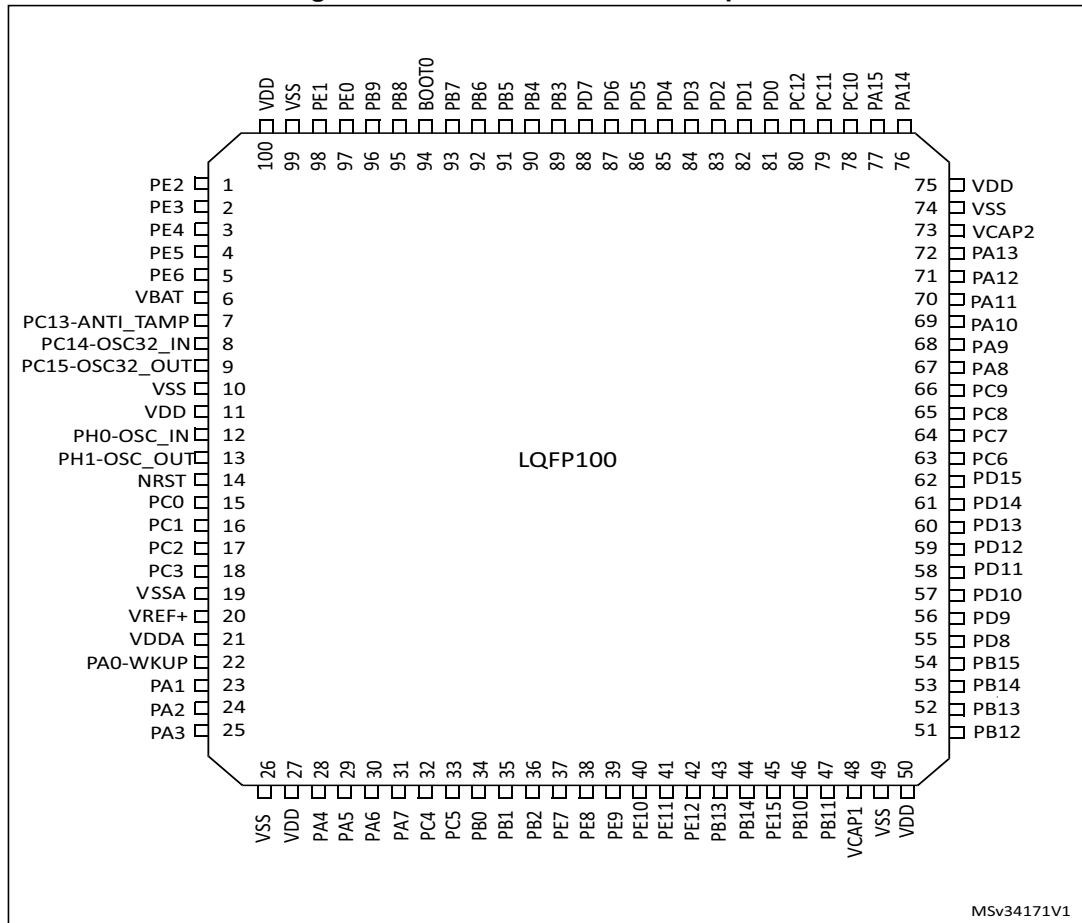
- LTDC interface color coding mappings into 24-bit interface:
 - 16-bit RGB, configurations 1, 2, and 3
 - 18-bit RGB, configurations 1 and 2
 - 24-bit RGB

Video mode pattern generator:

- Vertical and horizontal color bar generation without LTDC stimuli
- BER pattern without LTDC stimuli

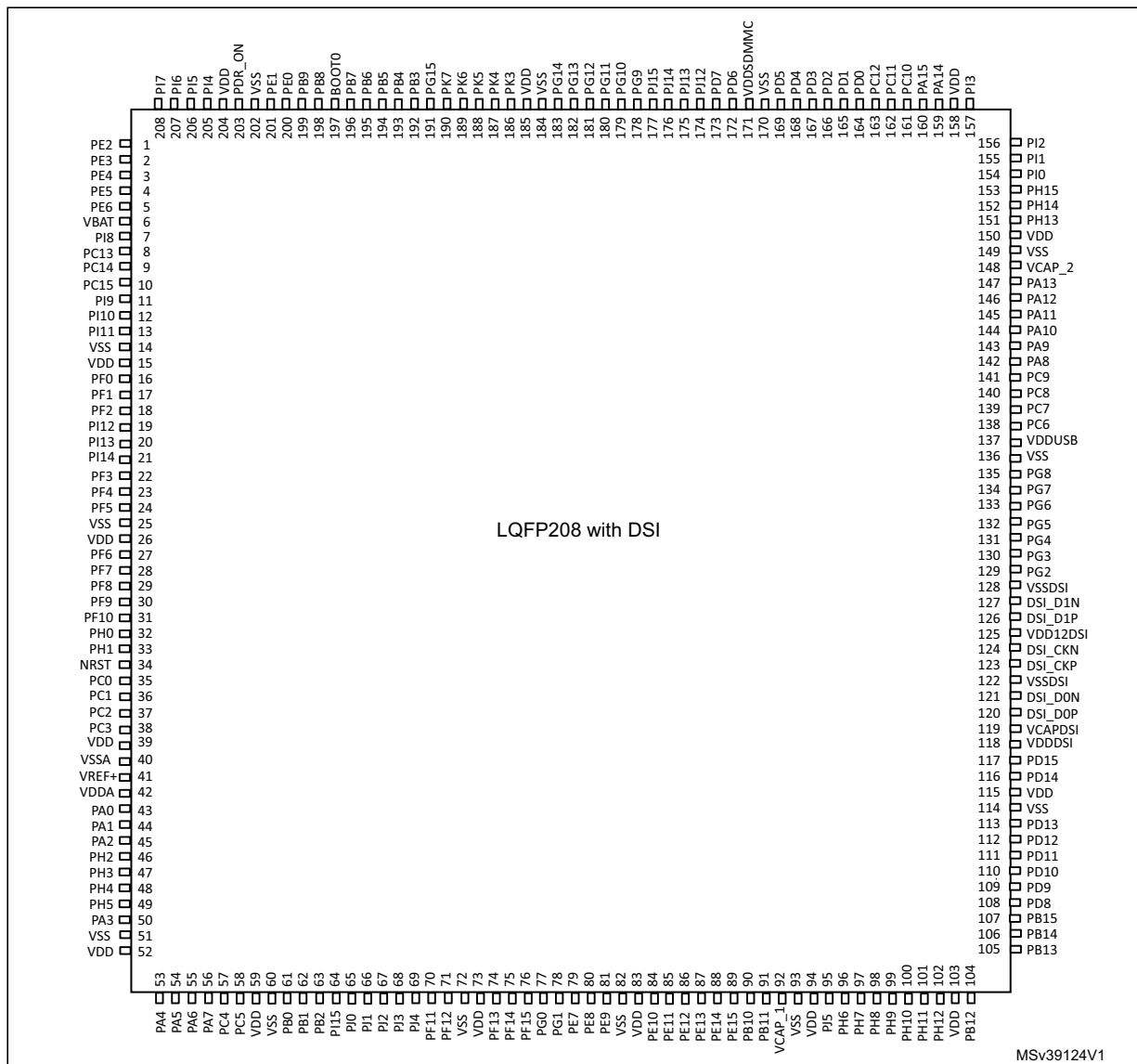
3 Pinouts and pin description

Figure 11. STM32F76xxx LQFP100 pinout



1. The above figure shows the package top view.

Figure 17. STM32F769xx LQFP208 pinout



1. The above figure shows the package top view.

Table 10. STM32F765xx, STM32F767xx, STM32F768Ax and STM32F769xx pin and ball definitions (continued)

Pin Number										Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
STM32F765xx STM32F767xx						STM32F768Ax STM32F769xx									
LQFP100	LQFP144	UFBGA176	LQFP176	LQFP208	TFBGA216	WLCSP180 ⁽¹⁾	LQFP176	LQFP208	TFBGA216						
-	-	-	-	60	L6	-	-	60	L6	VSS	S	-	-	-	-
34	46	R5	56	61	R5	P10	56	61	R5	PB0	I/O	FT	-	TIM1_CH2N, TIM3_CH3, TIM8_CH2N, DFSDM1_CKOUT, UART4_CTS, LCD_R3, OTG_HS_ULPI_D1, ETH_MII_RXD2, LCD_G1, EVENTOUT	ADC1_IN8, ADC2_IN8
35	47	R4	57	62	R4	J8	57	62	R4	PB1	I/O	FT	-	TIM1_CH3N, TIM3_CH4, TIM8_CH3N, DFSDM1_DATIN1, LCD_R6, OTG_HS_ULPI_D2, ETH_MII_RXD3, LCD_G0, EVENTOUT	ADC1_IN9, ADC2_IN9
36	48	M6	58	63	M5	J7	58	63	M5	PB2	I/O	FT	-	SAI1_SD_A, SPI3_MOSI/I2S3_SD, QUADSPI_CLK, DFSDM1_CKIN1, EVENTOUT	-
-	-	-	-	64	G4	NC	-	64	G4	PI15	I/O	FT	-	LCD_G2, LCD_R0, EVENTOUT	-
-	-	-	-	65	R6	NC	-	65	R6	PJ0	I/O	FT	-	LCD_R7, LCD_R1, EVENTOUT	-
-	-	-	-	66	R7	NC	-	66	R7	PJ1	I/O	FT	-	LCD_R2, EVENTOUT	-
-	-	-	-	67	P7	NC	-	67	P7	PJ2	I/O	FT	-	DSI_TE, LCD_R3, EVENTOUT	-
-	-	-	-	68	N8	NC	-	68	N8	PJ3	I/O	FT	-	LCD_R4, EVENTOUT	-
-	-	-	-	69	M9	NC	-	69	M9	PJ4	I/O	FT	-	LCD_R5, EVENTOUT	-
-	49	R6	59	70	P8	N9	59	70	P8	PF11	I/O	FT	-	SPI5_MOSI, SAI2_SD_B, FMC_SDNRAS, DCMI_D12, EVENTOUT	-
-	50	P6	60	71	M6	K7	60	71	M6	PF12	I/O	FT	-	FMC_A6, EVENTOUT	-

Table 12. STM32F765xx, STM32F767xx, STM32F768Ax and STM32F769xx alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS	I2C4/UART5/TIM1/2	TIM3/4/5	TIM8/9/10/11/LPTIM1/DFSDM1/CEC	I2C1/2/3/4/USART1/CEC	SPI1/I2S1/SPI2/I2S2/SPI3/I2S3/SPI4/5/6	SPI2/I2S2/SPI3/I2S3/SAI1/I2C4/UART4/DFSDM1	SPI2/I2S2/SPI3/I2S3/SPI6/USART1/2/3/UART5/DFSDM1/SPDIF	SPI6/SAI2/USART6/USART4/5/7/8/OTG_FS/SPDIF	CAN1/2/TIM12/13/14/QUADSPI/FMC/LCD	SAI2/QUADSPI/SDMMC2/DFSDM1/OTG_HS/OTG1_FS/LCD	I2C4/CAN3/SDMMC2/ETH	UART7/FMC/SDMMC1/MDIOS/OTG2_FS	DCMI/LCD/DSI	LCD	SYS
Port G	PG8	-	-	-	-	-	SPI6_NS	-	SPDIF_RX2	USART6_RTS	-	-	ETH_PPS_OUT	FMC_SD_CLK	-	LCD_G7	EVEN TOUT
	PG9	-	-	-	-	-	SPI1_MI	-	SPDIF_RX3	USART6_RX	QUADSPI_BK2_IO2	SAI2_FS_B	SDMMC2_D0	FMC_NE2/FMC_NCE	DCMI_V_SYNC	-	EVEN TOUT
	PG10	-	-	-	-	-	SPI1_NS	-	-	-	LCD_G3	SAI2_SD_B	SDMMC2_D1	FMC_NE3	DCMI_D2	LCD_B2	EVEN TOUT
	PG11	-	-	-	-	-	SPI1_SC	-	SPDIF_RX0	-	-	SDMMC2_D2	ETH_MII_TX_EN/ETH_RMII_TX_EN	-	DCMI_D3	LCD_B3	EVEN TOUT
	PG12	-	-	-	LPTIM1_IN1	-	SPI6_MI	-	SPDIF_RX1	USART6_RTS	LCD_B4	-	SDMMC2_D3	FMC_NE4	-	LCD_B1	EVEN TOUT
	PG13	TRACED0	-	-	LPTIM1_OUT	-	SPI6_SC	-	-	USART6_CTS	-	-	ETH_MII_TXD0/ETH_RMII_TXD0	FMC_A24	-	LCD_R0	EVEN TOUT
	PG14	TRACED1	-	-	LPTIM1_ETR	-	SPI6_MOSI	-	-	USART6_TX	QUADSPI_BK2_IO3	-	ETH_MII_TXD1/ETH_RMII_TXD1	FMC_A25	-	LCD_B0	EVEN TOUT
	PG15	-	-	-	-	-	-	-	-	USART6_CTS	-	-	-	FMC_SD_NCAS	DCMI_D13	-	EVEN TOUT

- When analog peripheral blocks such as ADCs, DACs, HSE, LSE, HSI, or LSI are ON, an additional power consumption should be considered.
- When the ADC is ON (ADON bit set in the ADC_CR2 register), add an additional power consumption of 1.73 mA per ADC for the analog part.
- Guaranteed by test in production.

Table 25. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory (Single bank mode, ART ON except prefetch / L1-cache ON) or SRAM on AXI (L1-cache ON), regulator ON

Symbol	Parameter	Conditions	f _{HCLK} (MHz)	Typ	Max ⁽¹⁾			Unit
					T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	
I _{DD}	Supply current in RUN mode	All peripherals enabled ⁽²⁾⁽³⁾	216	190	219	255	-	mA
			200	177	205	241	268	
			180	157	173	208	228	
			168	139	153	185	204	
			144	107	117	144	161	
			60	48	54	81	98	
			25	23	28	54	71	
		All peripherals disabled ⁽³⁾	216	92	104	150	-	
			200	86	97	143	170	
			180	76	85	119	140	
			168	67	75	107	126	
			144	52	58	84	101	
			60	23	28	54	71	
			25	11	15	42	56	

- Guaranteed by characterization results.
- When analog peripheral blocks such as ADCs, DACs, HSE, LSE, HSI, or LSI are ON, an additional power consumption should be considered.
- When the ADC is ON (ADON bit set in the ADC_CR2 register), add an additional power consumption of 1.73 mA per ADC for the analog part.

5.3.16 Memory characteristics

Flash memory

The characteristics are given at $T_A = -40$ to $105\text{ }^{\circ}\text{C}$ unless otherwise specified.

The devices are shipped to customers with the Flash memory erased.

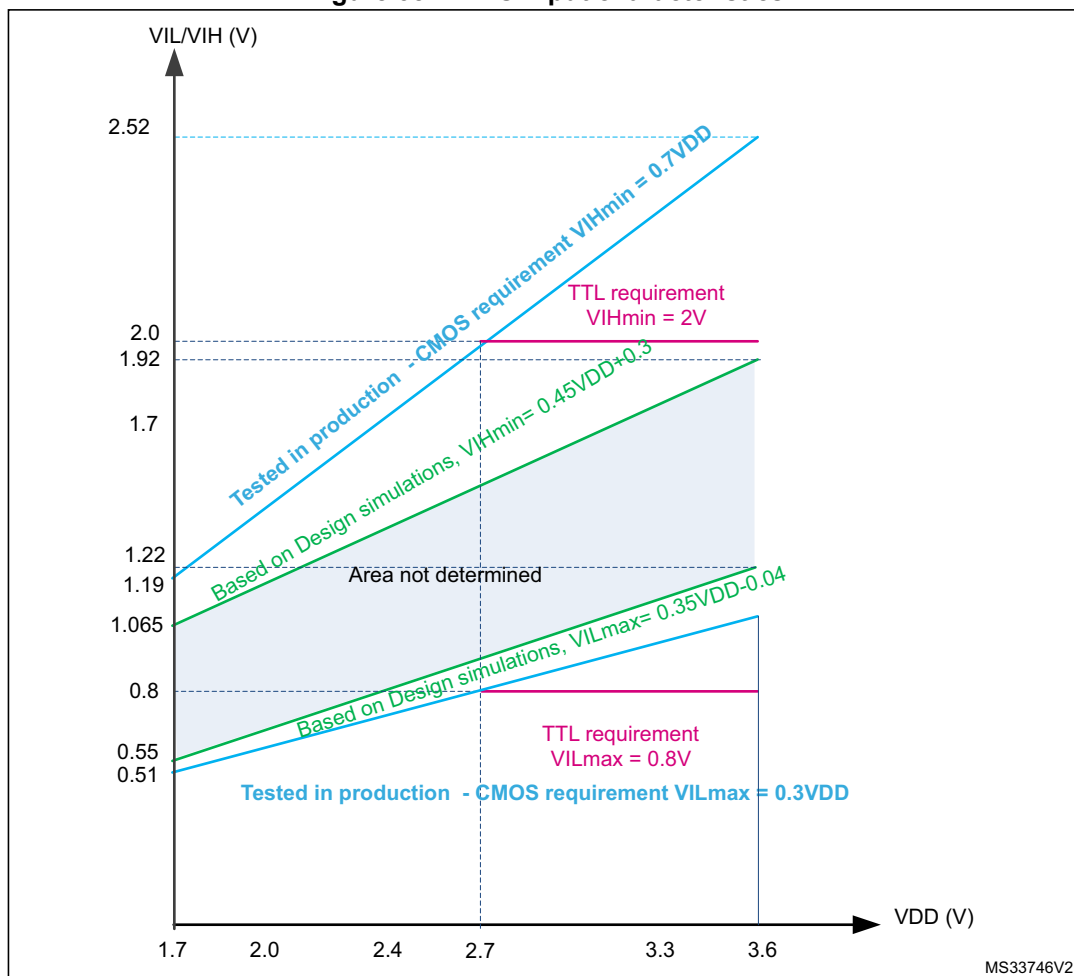
Table 55. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{DD}	Supply current	Write / Erase 8-bit mode, $V_{DD} = 1.7\text{ V}$	-	14	-	mA
		Write / Erase 16-bit mode, $V_{DD} = 2.1\text{ V}$	-	17	-	
		Write / Erase 32-bit mode, $V_{DD} = 3.3\text{ V}$	-	24	-	

**Table 56. Flash memory programming (single bank configuration
nDBANK=1)**

Symbol	Parameter	Conditions	Min ⁽¹⁾	Typ	Max ⁽¹⁾	Unit
t_{prog}	Word programming time	Program/erase parallelism (PSIZE) = x 8/16/32	-	16	100 ⁽²⁾	μs
$t_{ERASE32KB}$	Sector (32 KB) erase time	Program/erase parallelism (PSIZE) = x 8	-	400	800	ms
		Program/erase parallelism (PSIZE) = x 16	-	250	600	
		Program/erase parallelism (PSIZE) = x 32	-	200	500	
$t_{ERASE128KB}$	Sector (128 KB) erase time	Program/erase parallelism (PSIZE) = x 8	-	1100	2400	ms
		Program/erase parallelism (PSIZE) = x 16	-	800	1400	
		Program/erase parallelism (PSIZE) = x 32	-	500	1100	
$t_{ERASE256KB}$	Sector (256 KB) erase time	Program/erase parallelism (PSIZE) = x 8	-	2.1	4	s
		Program/erase parallelism (PSIZE) = x 16	-	1.5	2.6	
		Program/erase parallelism (PSIZE) = x 32	-	1	2	
t_{ME}	Mass erase time	Program/erase parallelism (PSIZE) = x 8	-	16	32	s
		Program/erase parallelism (PSIZE) = x 16	-	11	22	
		Program/erase parallelism (PSIZE) = x 32	-	8	16	

Figure 38. FT I/O input characteristics



Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to ± 8 mA, and sink or source up to ± 20 mA (with a relaxed V_{OL}/V_{OH}) except PC13, PC14, PC15 and PI8 which can sink or source up to ± 3 mA. When using the PC13 to PC15 and PI8 GPIOs in output mode, the speed should not exceed 2 MHz with a maximum load of 30 pF.

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 5.2](#). In particular:

- The sum of the currents sourced by all the I/Os on V_{DD} , plus the maximum Run consumption of the MCU sourced on V_{DD} , cannot exceed the absolute maximum rating ΣI_{VDD} (see [Table 15](#)).
- The sum of the currents sunk by all the I/Os on V_{SS} plus the maximum Run consumption of the MCU sunk on V_{SS} cannot exceed the absolute maximum rating ΣI_{VSS} (see [Table 15](#)).

Output voltage levels

Unless otherwise specified, the parameters given in [Table 66](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 17](#). All I/Os are CMOS and TTL compliant.

Table 66. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	CMOS port ⁽²⁾ $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin except PC14	CMOS port ⁽²⁾ $I_{IO} = -8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD} - 0.4$	-	
$V_{OH}^{(3)}$	Output high level voltage for PC14	CMOS port ⁽²⁾ $I_{IO} = -2 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD} - 0.4$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	TTL port ⁽²⁾ $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin except PC14	TTL port ⁽²⁾ $I_{IO} = -8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	2.4	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	$I_{IO} = +20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	1.3 ⁽⁴⁾	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin except PC14	$I_{IO} = -20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD} - 1.3^{(4)}$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	$I_{IO} = +6 \text{ mA}$ $1.8 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4 ⁽⁴⁾	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin except PC14	$I_{IO} = -6 \text{ mA}$ $1.8 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD} - 0.4^{(4)}$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	$I_{IO} = +4 \text{ mA}$ $1.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4 ⁽⁵⁾	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin except PC14	$I_{IO} = -4 \text{ mA}$ $1.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD} - 0.4^{(5)}$	-	
$V_{OH}^{(3)}$	Output high level voltage for PC14	$I_{IO} = -1 \text{ mA}$ $1.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD} - 0.4^{(5)}$	-	

1. The I_{IO} current sunk by the device must always respect the absolute maximum rating specified in [Table 15](#) and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS} .
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. The I_{IO} current sourced by the device must always respect the absolute maximum rating specified in [Table 15](#) and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VDD} .
4. Based on characterization data.
5. Guaranteed by design.

Input/output AC characteristics

The definition and values of input/output AC characteristics are given in [Figure 39](#) and [Table 67](#), respectively.

SPI interface characteristics

Unless otherwise specified, the parameters given in [Table 85](#) for the SPI interface are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 17](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C = 30 pF
- Measurement points are done at CMOS levels: $0.5V_{\text{DD}}$

Refer to [Section 5.3.20: I/O port characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI).

Table 85. SPI dynamic characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{SCK} $1/t_{\text{c(SCK)}}$	SPI clock frequency	Master mode SPI1,4,5,6 $2.7 \leq V_{\text{DD}} \leq 3.6$	-	-	54 ⁽²⁾	MHz
		Master mode SPI1,4,5,6 $1.71 \leq V_{\text{DD}} \leq 3.6$			27	
		Master transmitter mode SPI1,4,5,6 $1.71 \leq V_{\text{DD}} \leq 3.6$			54	
		Slave receiver mode SPI1,4,5,6 $1.71 \leq V_{\text{DD}} \leq 3.6$			54	
		Slave mode transmitter/full duplex SPI1,4,5,6 $2.7 \leq V_{\text{DD}} \leq 3.6$			50 ⁽³⁾	
		Slave mode transmitter/full duplex SPI1,4,5,6 $1.71 \leq V_{\text{DD}} \leq 3.6$			37 ⁽³⁾	
		Master & Slave mode SPI2,3 $1.71 \leq V_{\text{DD}} \leq 3.6$			27	
tsu(NSS)	NSS setup time	Slave mode, SPI presc = 2	$4 \cdot T_{\text{PLCK}}$	-	-	ns
th(NSS)	NSS hold time	Slave mode, SPI presc = 2	$2 \cdot T_{\text{PLCK}}$	-	-	
tw(SCKH) tw(SCKL)	SCK high and low time	Master mode	$T_{\text{PLCK}} - 2$	T_{PLCK}	$T_{\text{PLCK}} + 2$	

JATG/SWD characteristics

Unless otherwise specified, the parameters given in [Table 87](#) for JTAG/SWD are derived from tests performed under the ambient temperature, f_{HCLK} frequency and VDD supply voltage conditions summarized in [Table 17](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C=30 pF
- Measurement points are performed at CMOS levels: $0.5V_{DD}$

Refer to [Section 5.3.20: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SCK,SD,WS).

Table 87. Dynamics characteristics: JTAG characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
F_{pp}	TCK clock frequency	$2.7V < VDD < 3.6V$	-	-	40	MHz
$1/t_{c(TCK)}$		$1.71 < VDD < 3.6V$	-	-	35	
$t_{w(TCKH)}$	SCK high and low time	-	$T_{PCLK} - 1$	T_{PCLK}	$T_{PCLK} + 1$	ns
$t_{w(TCKL)}$						
$t_{su(TMS)}$	TMS input setup time	-	3	-	-	
$t_{h(TMS)}$	TMS input hold time	-	0	-	-	
$t_{su(TDI)}$	TDI input setup time	-	0.5	-	-	
$t_{h(TDI)}$	TDI input hold time	-	2	-	-	
$t_{ov(TDO)}$	TDO output valid time	$2.7V < VDD < 3.6V$	-	9	11	
		$1.71 < VDD < 3.6V$	-	9	13	
$t_{oh(TDO)}$	TDO output hold time	-	7.5	-	-	

Table 104. Asynchronous multiplexed PSRAM/NOR read timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$3T_{HCLK} - 1$	$3T_{HCLK} + 1$	ns
$t_{v(NOE_NE)}$	FMC_NEx low to FMC_NOE low	$2T_{HCLK}$	$2T_{HCLK} + 0.5$	
$t_{tw(NOE)}$	FMC_NOE low time	$T_{HCLK} - 1$	$T_{HCLK} + 1$	
$t_{h(NE_NOE)}$	FMC_NOE high to FMC_NE high hold time	0	-	
$t_{v(A_NE)}$	FMC_NEx low to FMC_A valid	-	0.5	
$t_{v(NADV_NE)}$	FMC_NEx low to FMC_NADV low	0	0.5	
$t_{w(NADV)}$	FMC_NADV low time	$T_{HCLK} - 0.5$	$T_{HCLK} + 1$	
$t_{h(AD_NADV)}$	FMC_AD(address) valid hold time after FMC_NADV high	$T_{HCLK} + 0.5$	-	
$t_{h(A_NOE)}$	Address hold time after FMC_NOE high	$T_{HCLK} - 0.5$	-	
$t_{h(BL_NOE)}$	FMC_BL time after FMC_NOE high	0	-	
$t_{v(BL_NE)}$	FMC_NEx low to FMC_BL valid	-	0.5	
$t_{su(Data_NE)}$	Data to FMC_NEx high setup time	$T_{HCLK} - 1$	-	
$t_{su(Data_NOE)}$	Data to FMC_NOE high setup time	$T_{HCLK} - 1$	-	
$t_{h(Data_NE)}$	Data hold time after FMC_NEx high	0	-	
$t_{h(Data_NOE)}$	Data hold time after FMC_NOE high	0	-	

1. Guaranteed by characterization results.

Table 105. Asynchronous multiplexed PSRAM/NOR read-NWAIT timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$8T_{HCLK} - 1$	$8T_{HCLK} + 1$	ns
$t_{w(NOE)}$	FMC_NWE low time	$5T_{HCLK} - 1.5$	$5T_{HCLK} + 0.5$	
$t_{su(NWAIT_NE)}$	FMC_NWAIT valid before FMC_NEx high	$5T_{HCLK} + 1.5$	-	
$t_{h(NE_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$4T_{HCLK} + 1$	-	

1. Guaranteed by characterization results.